

STD90N03L STD90N03L-1

N-channel 30V - 0.005Ω - 80A - DPAK/IPAK STripFET™ III Power MOSFET

General features

Туре	V _{DSS}	R _{DS(on)}	Ι _D
STD90N03L	30V	0.0057Ω	80A ⁽¹⁾
STD90N03L-1	30V	0.0057Ω	80A ⁽¹⁾

- 1. Pulse width limited by safe operating area
- R_{DS(on)}*Q_g industry's benchmark
- Conduction losses reduced
- Switching losses reduced
- Low threshold device

Description

This device utilizes the latest advanced design rules of ST's proprietary STripFET[™] technology. This is suitable for the most demanding DC-DC converter application where high efficiency is to be achieved.

Applications

Switching applications



Internal schematic diagram



Order codes

Part number	Marking	Package	Packaging
STD90N03L	D90N03L	DPAK	Tape & reel
STD90N03L-1	D90N03L-1	IPAK	Tube

October	2006

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0050	Revision history



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Electrical ratings

Table 1.	Absolute	maximum	ratings
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Symbol	Parameter	Value	Unit				
V _{DS}	Drain-source voltage ($V_{GS} = 0$)	30	V				
V _{GS}	Gate-source voltage	±20	V				
I _D ⁽¹⁾	Drain current (continuous) at $T_C = 25^{\circ}C$	80	А				
I _D	Drain current (continuous) at T _C =100°C	64	А				
I _{DM} ⁽²⁾	Drain current (pulsed)	320	А				
P _{TOT}	Total dissipation at $T_{C} = 25^{\circ}C$	95	W				
	Derating factor	0.63	W/°C				
E _{AS} ⁽³⁾	Single pulse avalanche energy	350	mJ				
T _J T _{stg}	-55 to 175 °C						
1. Value limited by wire bonding							
2. Pulse width limited by safe operating area							
3. Starting T							

Table 2. Thermal data

	Symbol	Parameter	Value	Unit
	R _{thj-case}	Thermal resistance junction-case max	1.58	°C/W
	R _{thj-amb}	Thermal resistance junction-ambient max	100	°C/W
	т	Maximum lead temperature for soldering purpose	275	°C
Obsole	je			

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Electrical characteristics 2

(T_{CASE}=25°C unless otherwise specified)

Table 5.	On/on states					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 250μA, V _{GS} = 0	30			V
I _{DSS}	Zero gate voltage drain current ($V_{GS} = 0$)	V _{DS} = 30V V _{DS} = 30V, Tc=125°C			1 10	μΑ μΑ
I _{GSS}	Gate body leakage current (V _{DS} = 0)	$V_{GS} = \pm 20V$			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1	32		V
R _{DS(on)}	Static drain-source on resistance	V_{GS} = 10V, I _D = 40A V_{GS} = 5V, I _D = 40A	540	0.005 0.007	0.0057 0.0011	Ω Ω
Table 4.	Dynamic	olete				
0	Demonster			T		11

Table 3. **On/off states**

Table 4. Dynamic

	Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
	C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} =25V, f=1MHz, V _{GS} =0		2805 549 76		pF pF pF
	Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V _{DD} =15V, I _D = 80A V _{GS} =5V (see Figure 13)		22 10 7	32	nC nC nC
sole	R _G	Gate input resistance	f=1MHz Gate Bias Bias=0 Test Signal Level=20mV open drain		1.2		Ω
0,02	Table 5.	Switching times					

Table 5. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on delay time Rise time	V_{DD} =15V, I _D =40A, R _G =4.7 Ω , V _{GS} =5V (see Figure 12)		19 135		ns ns
t _{d(off)} t _f	Turn-off delay time Fall time	V _{DD} =15V, I _D =40A, R _G =4.7Ω, V _{GS} =5V (see Figure 12)		24 33		ns ns



Symbo	Parameter	Test conditions	Min.	Тур.	Max.	Uni
I _{SD}	Source-drain current				80	А
I _{SDM} ⁽¹	Source-drain current (pulsed)				320	А
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} =40A, V _{GS} =0			1.3	V
t _{rr}	Reverse recovery time	I _{SD} =80A, di/dt = 100A/µs,		36		ns
Q _{rr}	Reverse recovery charge Reverse recovery current width limited by safe operating area d: pulse duration=300µs, duty cycle	V _{DD} =19 V, Tj= 150°C		32		μC
I _{RRM}	Reverse recovery current	(see Figure 15)		1.8		A
1. Pulse	width limited by safe operating area	l			IC	
2. Pulse	d: pulse duration=300µs, duty cycle	1.5%				
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Table 6. Source drain diode



2.1 Electrical characteristics (curves)



Figure 2. Thermal impedance



HV34710 HV34700 C(pF) Vgs(V)f=1MHz Vgs=0V VDD=15V ID=80A 5000 8 4000 6 Ciss 3000 4 2000 2 1000 Coss Crs 25 Vos(V) 10 15 20 0 10 20 30 40 Q₀(nC) 0 5

Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations







Figure 11. Source-drain diode forward characteristics



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3 Test circuit

Figure 12. Switching times test circuit for resistive load





Figure 13. Gate charge test circuit

Figure 14. Test circuit for inductive load switching and diode recovery times

Figure 15. Unclamped Inductive load test circuit



Appendix A



Figure 16. Buck Converter: Power Losses Estimation

The power losses associated with the FETs in a Synchronous Buck converter can be estimated using the equations shown in the table below. The formulas give a good approximation, for the sake of performance comparison, of how different pairs of devices affect the converter efficiency. However a very important parameter, the working temperature, is not considered. The real device behavior is really dependent on how the heat generated inside the devices is removed to allow for a safer working junction temperature.

The low side (SW2) device requires:

- Very low R_{DS(on)} to reduce conduction losses
- Small Qgls to reduce the gate charge losses
- Small Coss to reduce losses due to output capacitance
- Small Qrr to reduce losses on SW1 during its turn-on
- The Cgd/Cgs ratio lower than Vth/Vgg ratio especially with low drain to source
- voltage to avoid the cross conduction phenomenon;

The high side (SW1) device requires:

- Small Rg and Ls to allow higher gate current peak and to limit the voltage feedback on the gate
- Small Qg to have a faster commutation and to reduce gate charge losses
- Low R_{DS(on)} to reduce the conduction losses.



		Fower iosses calculation	
		High Side Switching (SW1)	Low Side Switch (SW2)
P _{conc}	duction	$R_{DS(on)SW1} * I_L^2 * \delta$	$R_{DS(on)SW2} * I_L^2 * (1 - \delta)$
P _{swit}	tching	$\mathbf{V}_{\text{in}} * (\mathbf{Q}_{\text{gsth}(\text{SW1})} + \mathbf{Q}_{\text{gd}(\text{SW1})}) * \mathbf{f} * \frac{I_L}{I_g}$	Zero voltage switching
Ρ	Recovery (1)	Not applicable	$V_{in} * Q_{rr(SW2)} * f$
P _{diode}	Conduction	Not applicable	$V_{f(SW2)} * I_L * t_{deadtime} * f$
Pgate	ə(QG)	$Q_{g(SW1)} * V_{gg} * f$	$Q_{gls(SW2)} * V_{gg} * f$
P _{Qoss}		$\frac{V_{in} * Q_{oss(SW1)} * f}{2}$	$\frac{V_{in} * Q_{oss(SW2)} * f}{2}$
. Dissipated	by SW1 during	a turn-on	•

Table 7. Power losses calculation

1. Dissipated by SW1 during turn-on

Table 8. Paramiters meaning

	Parameter	Meaning
	d	Duty-cycle
01050	Q _{gsth}	Post threshold gate charge
	Q _{gls}	Third quadrant gate charge
	Pconduction	On state losses
	P _{switching}	On-off transition losses
	P _{diode}	Conduction and reverse recovery diode losses
	P _{gate}	Gate drive losses
	P _{Qoss}	Output capacitance losses

4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

Obsolete Product(s). Obsolete Product(s)



DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A3	0.7		1.3	0.027		0.051
В	0.64		0.9	0.025		0.031
B2	5.2		5.4	0.204		0.212
B3			0.85			0.033
B5		0.3			0.012	0
B6			0.95			0.037
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
E	6.4		6.6	0.252		0.260
G	4.4		4.6	0.173		0.181
Н	15.9		16.3	0.626		0.641
L	9		9.4	0.354		0.370
L1	0.8		1.2	0.031		0.047
L2		0.8	1		0.031	0.039

TO-251 (IPAK) MECHANICAL DATA



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5 Packaging mechanical data



DPAK FOOTPRINT

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6 Revision history

Table 9. Revision history

Date	Revision	Changes
20-Oct-2006	1	Initial release.

obsolete Product(s). Obsolete Product(s)

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